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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	196
Number of Logic Elements/Cells	466
Total RAM Bits	6272
Number of I/O	112
Number of Gates	10000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs10-4tq144c

Spartan and Spartan-XL devices provide system clock rates exceeding 80 MHz and internal performance in excess of 150 MHz. In addition to the conventional benefit of high volume programmable logic solutions, Spartan series FPGAs also offer on-chip edge-triggered single-port and dual-port RAM, clock enables on all flip-flops, fast carry logic, and many other features.

The Spartan/XL families leverage the highly successful XC4000 architecture with many of that family's features and benefits. Technology advancements have been derived from the XC4000XLA process developments.

Logic Functional Description

The Spartan series uses a standard FPGA structure as shown in Figure 1, page 2. The FPGA consists of an array of configurable logic blocks (CLBs) placed in a matrix of routing channels. The input and output of signals is achieved through a set of input/output blocks (IOBs) forming a ring around the CLBs and routing channels.

- CLBs provide the functional elements for implementing the user's logic.
- IOBs provide the interface between the package pins and internal signal lines.
- Routing channels provide paths to interconnect the inputs and outputs of the CLBs and IOBs.

The functionality of each circuit block is customized during configuration by programming internal static memory cells. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA.

Configurable Logic Blocks (CLBs)

The CLBs are used to implement most of the logic in an FPGA. The principal CLB elements are shown in the simplified block diagram in Figure 2. There are three look-up tables (LUT) which are used as logic function generators, two flip-flops and two groups of signal steering multiplexers. There are also some more advanced features provided by the CLB which will be covered in the **Advanced Features Description**, page 13.

Function Generators

Two 16 x 1 memory look-up tables (F-LUT and G-LUT) are used to implement 4-input function generators, each offering unrestricted logic implementation of any Boolean function of up to four independent input signals (F1 to F4 or G1 to G4). Using memory look-up tables the propagation delay is independent of the function implemented.

A third 3-input function generator (H-LUT) can implement any Boolean function of its three inputs. Two of these inputs are controlled by programmable multiplexers (see box "A" of Figure 2). These inputs can come from the F-LUT or G-LUT outputs or from CLB inputs. The third input always comes from a CLB input. The CLB can, therefore, implement certain functions of up to nine inputs, like parity checking. The three LUTs in the CLB can also be combined to do any arbitrarily defined Boolean function of five inputs.

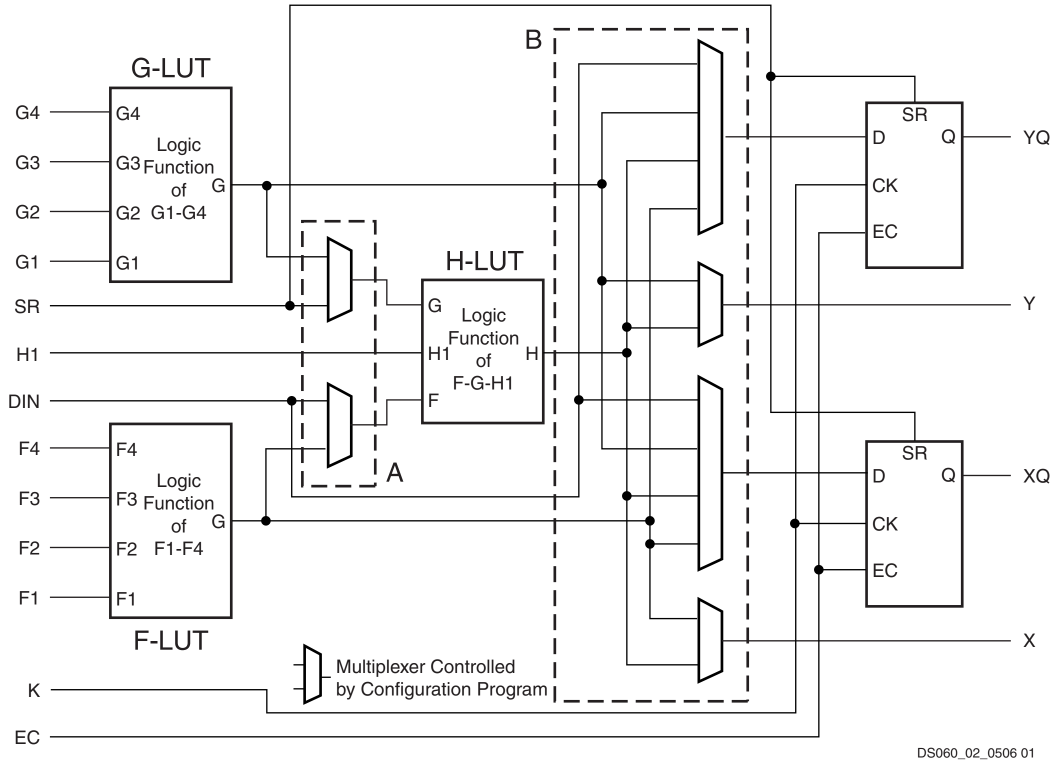


Figure 2: **Spartan/XL Simplified CLB Logic Diagram (some features not shown)**

A CLB can implement any of the following functions:

- Any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables

  Note: When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.
- Any single function of five variables
- Any function of four variables together with some functions of six variables
- Some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

Flip-Flops

Each CLB contains two flip-flops that can be used to register (store) the function generator outputs. The flip-flops and function generators can also be used independently (see Figure 2). The CLB input DIN can be used as a direct input to either of the two flip-flops. H1 can also drive either flip-flop via the H-LUT with a slight additional delay.

The two flip-flops have common clock (CK), clock enable (EC) and set/reset (SR) inputs. Internally both flip-flops are also controlled by a global initialization signal (GSR) which is described in detail in **Global Signals: GSR and GTS**, page 20.

Latches (Spartan-XL Family Only)

The Spartan-XL family CLB storage elements can also be configured as latches. The two latches have common clock (K) and clock enable (EC) inputs. Functionality of the storage element is described in Table 2.

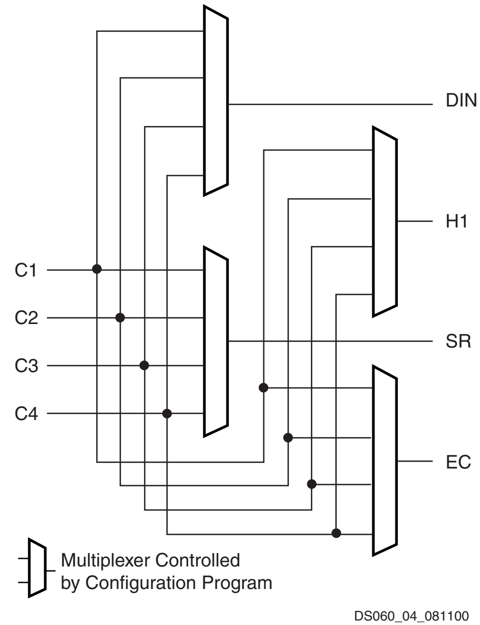


Figure 4: **CLB Control Signal Interface**

The four internal control signals are:

- EC: Enable Clock
- SR: Asynchronous Set/Reset or H function generator Input 0
- DIN: Direct In or H function generator Input 2
- H1: H function generator Input 1.

Input/Output Blocks (IOBs)

User-configurable input/output blocks (IOBs) provide the interface between external package pins and the internal logic. Each IOB controls one package pin and can be configured for input, output, or bidirectional signals. Figure 6 shows a simplified functional block diagram of the Spartan/XL FPGA IOB.

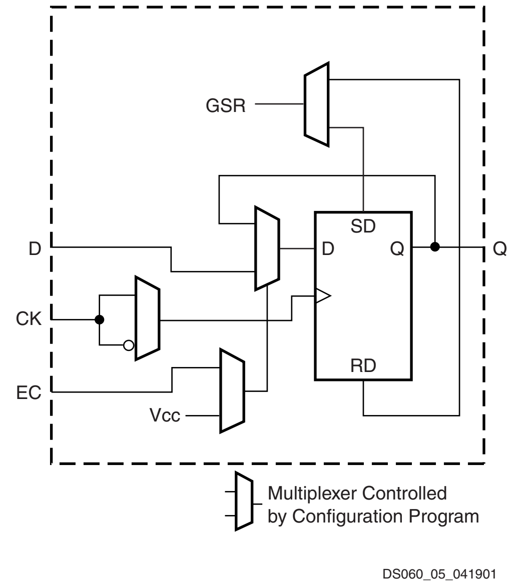


Figure 5: **IOB Flip-Flop/Latch Functional Block Diagram**

IOB Input Signal Path

The input signal to the IOB can be configured to either go directly to the routing channels (via I1 and I2 in Figure 6) or to the input register. The input register can be programmed as either an edge-triggered flip-flop or a level-sensitive latch. The functionality of this register is shown in Table 3, and a simplified block diagram of the register can be seen in Figure 5.

Table 3: **Input Register Functionality**

Mode	CK	EC	D	Q
Power-Up or GSR	X	X	X	SR
Flip-Flop	_/‾	1*	D	D
	0	X	X	Q
Latch	1	1*	X	Q
	0	1*	D	D
Both	X	0	X	Q

Legend:

X	Don't care.
_/‾	Rising edge (clock not inverted).
SR	Set or Reset value. Reset is default.
0*	Input is Low or unconnected (default value)
1*	Input is High or unconnected (default value)

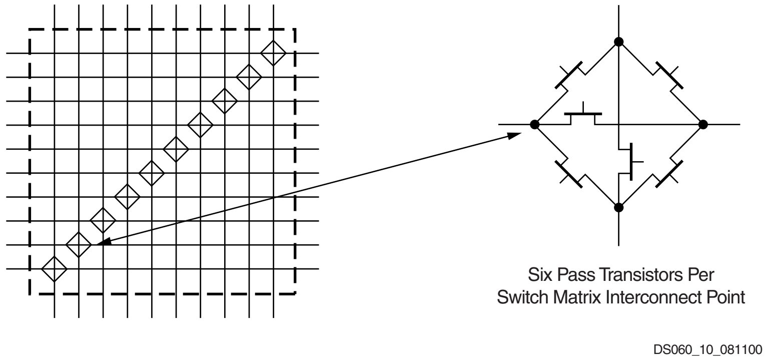


Figure 10: **Programmable Switch Matrix**

Double-Length Lines

The double-length lines consist of a grid of metal segments, each twice as long as the single-length lines: they run past two CLBs before entering a PSM. Double-length lines are grouped in pairs with the PSMs staggered, so that each line goes through a PSM at every other row or column of CLBs (see Figure 8).

There are four vertical and four horizontal double-length lines associated with each CLB. These lines provide faster signal routing over intermediate distances, while retaining routing flexibility.

Longlines

Longlines form a grid of metal interconnect segments that run the entire length or width of the array. Longlines are intended for high fan-out, time-critical signal nets, or nets that are distributed over long distances.

Each Spartan/XL device longline has a programmable splitter switch at its center. This switch can separate the line into two independent routing channels, each running half the width or height of the array.

Routing connectivity of the longlines is shown in Figure 8. The longlines also interface to some 3-state buffers which is described later in **3-State Long Line Drivers**, page 19.

I/O Routing

Spartan/XL devices have additional routing around the IOB ring. This routing is called a VersaRing. The VersaRing facilitates pin-swapping and redesign without affecting board layout. Included are eight double-length lines, and four longlines.

Global Nets and Buffers

The Spartan/XL devices have dedicated global networks. These networks are designed to distribute clocks and other high fanout control signals throughout the devices with minimal skew.

Four vertical longlines in each CLB column are driven exclusively by special global buffers. These longlines are in addition to the vertical longlines used for standard interconnect. In the 5V Spartan devices, the four global lines can be driven by either of two types of global buffers; Primary Global buffers (BUFGP) or Secondary Global buffers (BUFGS). Each of these lines can be accessed by one particular Primary Global buffer, or by any of the Secondary Global buffers, as shown in Figure 11. In the 3V Spartan-XL devices, the four global lines can be driven by any of the eight Global Low-Skew Buffers (BUFGLS). The clock pins of every CLB and IOB can also be sourced from local interconnect.

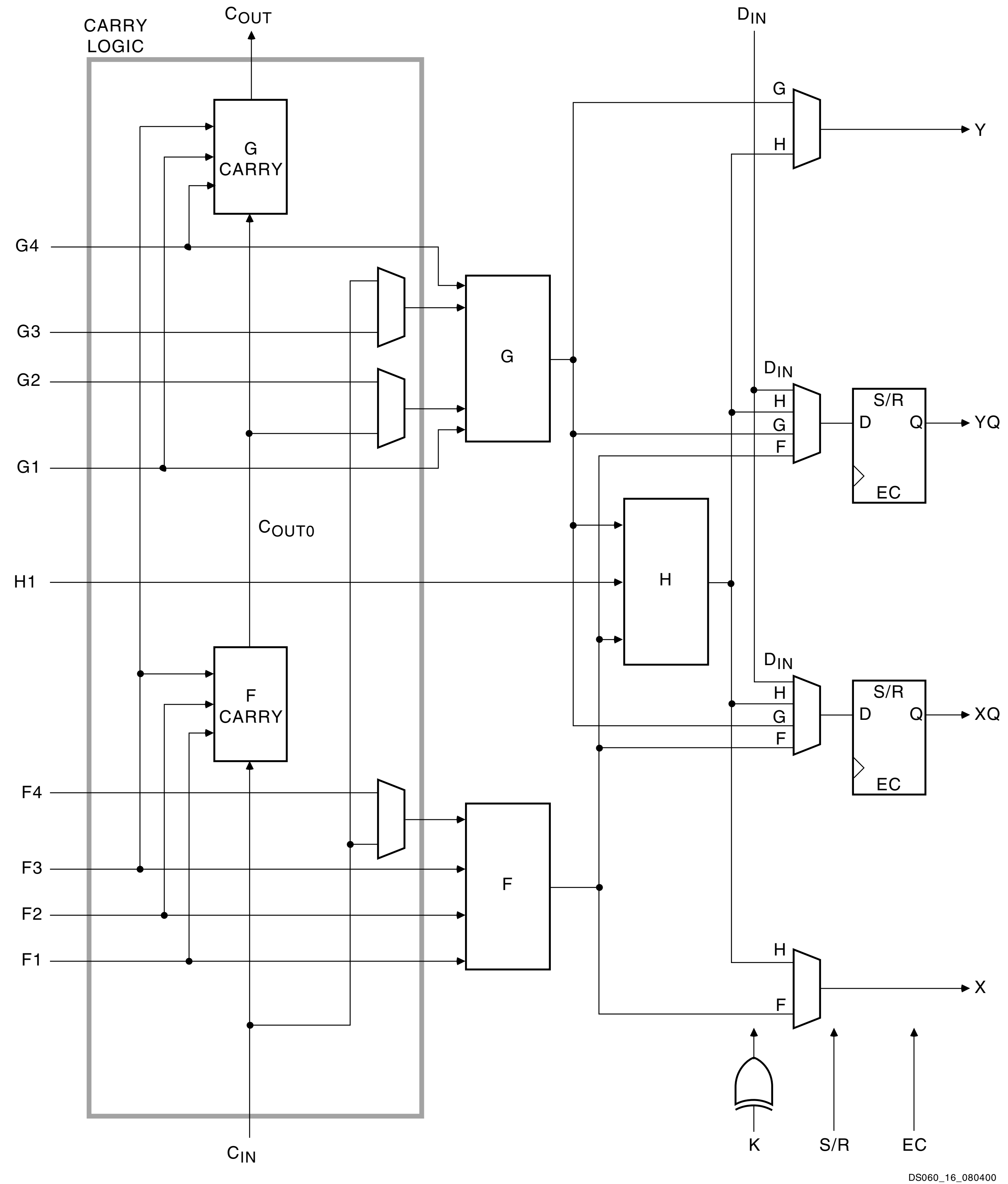


Figure 16: **Fast Carry Logic in Spartan/XL CLB**

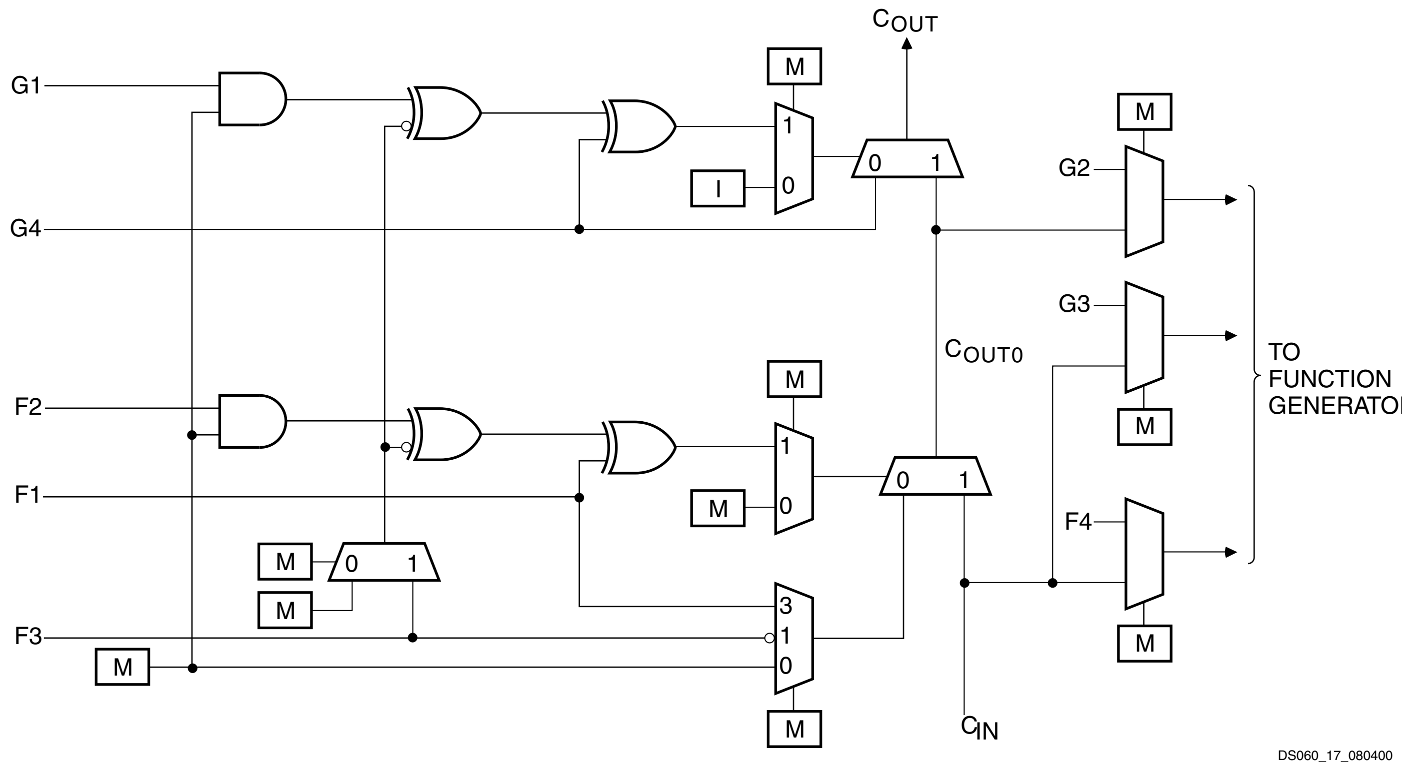


Figure 17: **Detail of Spartan/XL Dedicated Carry Logic**

3-State Long Line Drivers

A pair of 3-state buffers is associated with each CLB in the array. These 3-state buffers (BUFT) can be used to drive signals onto the nearest horizontal longlines above and below the CLB. They can therefore be used to implement multiplexed or bidirectional buses on the horizontal longlines, saving logic resources.

There is a weak keeper at each end of these two horizontal longlines. This circuit prevents undefined floating levels. However, it is overridden by any driver.

The buffer enable is an active High 3-state (i.e., an active Low enable), as shown in Table 11.

Three-State Buffer Example

Figure 18 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

Pay particular attention to the polarity of the T pin when using these buffers in a design. Active High 3-state (T) is identical to an active Low output enable, as shown in Table 11.

Table 11: **Three-State Buffer Functionality**

IN	T	OUT
X	1	Z
IN	0	IN

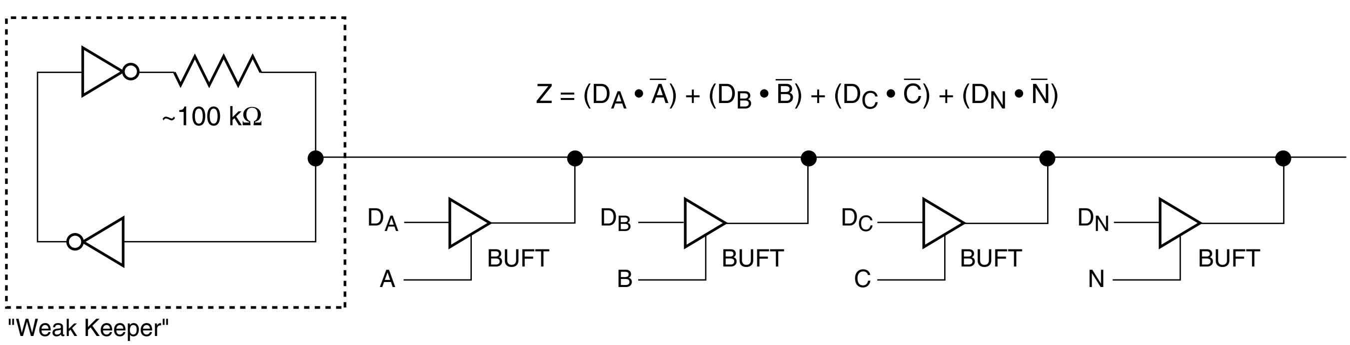


Figure 18: **3-state Buffers Implement a Multiplexer**

Table 12: **Boundary Scan Instructions**

Instruction			Test Selected	TDO Source	I/O Data Source
I2	I1	I0			
0	0	0	EXTEST	DR	DR
0	0	1	SAMPLE/ PRELOAD	DR	Pin/Logic
0	1	0	USER 1	BSCAN. TDO1	User Logic
0	1	1	USER 2	BSCAN. TDO2	User Logic
1	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	CONFIGURE	DOUT	Disabled
1	1	0	IDCODE (Spartan-XL only)	IDCODE Register	-
1	1	1	BYPASS	Bypass Register	-

Bit Sequence

The bit sequence within each IOB is: In, Out, 3-state. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

The first two bits in the I/O data register are TDO.T and TDO.O, which can be used for the capture of internal signals. The final bit is BSCANT.UPD, which can be used to drive an internal net. These locations are primarily used by Xilinx for internal testing.

From a cavity-up view of the chip (as shown in the FPGA Editor), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 21. The device-specific pinout tables for the Spartan/XL devices include the boundary scan locations for each IOB pin.

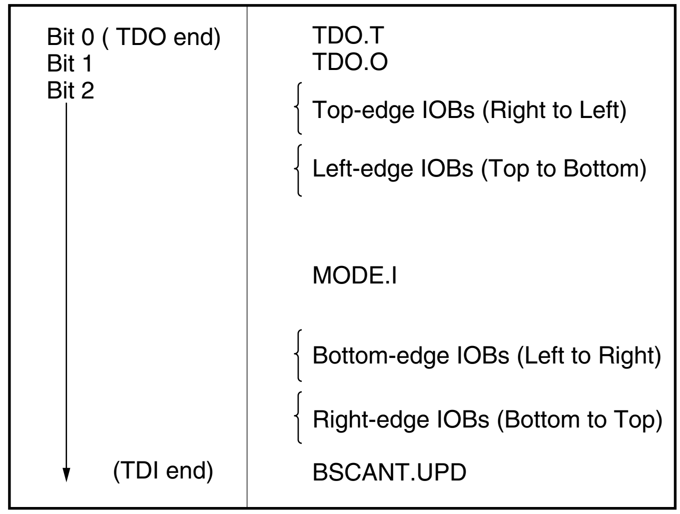


Figure 21: **Boundary Scan Bit Sequence**

BSDL (Boundary Scan Description Language) files for Spartan/XL devices are available on the Xilinx website in the File Download area. Note that the 5V Spartan devices and 3V Spartan-XL devices have different BSDL files.

Including Boundary Scan in a Design

If boundary scan is only to be used during configuration, no special elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, place the BSCAN library symbol and connect the TDI, TMS, TCK and TDO pad symbols to the appropriate pins, as shown in Figure 22.

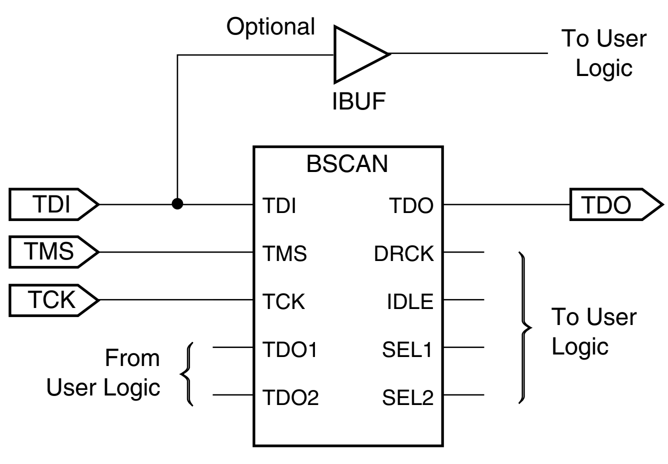


Figure 22: **Boundary Scan Example**

figuration are shown in Table 14 and Table 15.

Table 14: **Pin Functions During Configuration (Spartan Family Only)**

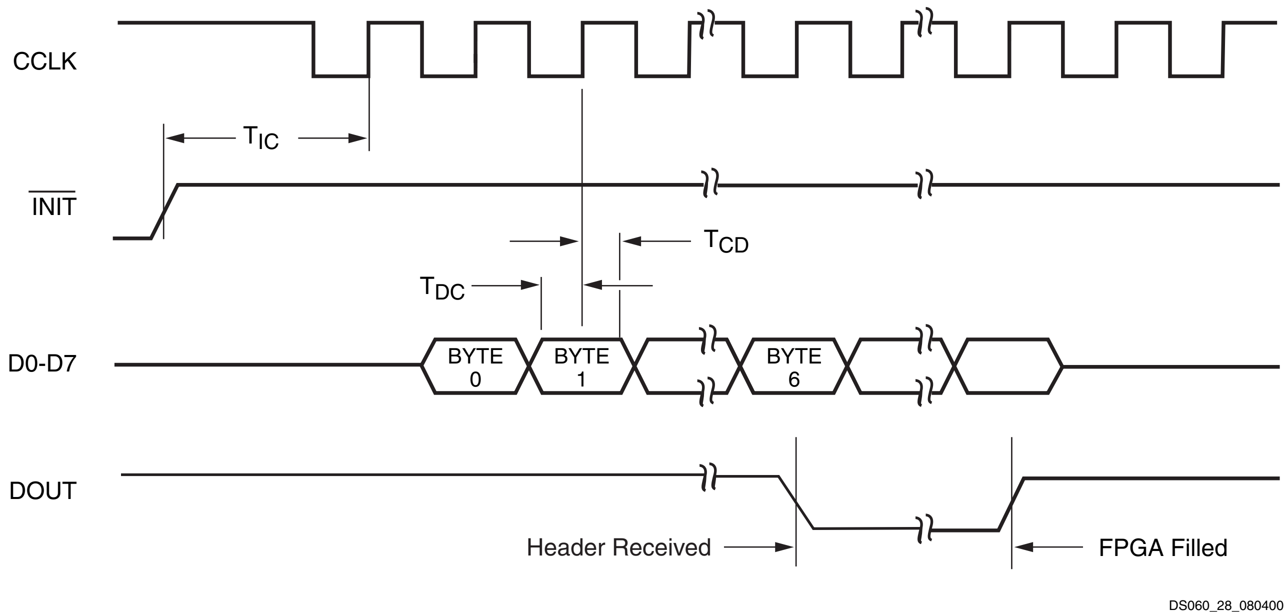
Configuration Mode (MODE Pin)		
Slave Serial (High)	**Master Serial (Low)**	**User Operation**
MODE (I)	MODE (I)	MODE
HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)
DIN (I)	DIN (I)	I/O
DOUT	DOUT	SGCK4-I/O
TDI	TDI	TDI-I/O
TCK	TCK	TCK-I/O
TMS	TMS	TMS-I/O
TDO	TDO	TDO-(O)
		ALL OTHERS

Notes:
1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3. $\overline{\text{INIT}}$ is an open-drain output during configuration.

Table 15: **Pin Functions During Configuration (Spartan-XL Family Only)**

CONFIGURATION MODE <M1:M0>			
Slave Serial [1:1]	**Master Serial [1:0]**	**Express [0:X]**	**User Operation**
M1 (High) (I)	M1 (High) (I)	M1(Low) (I)	M1
M0 (High) (I)	M0 (Low) (I)	M0 (I)	M0
HDC (High)	HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (I)
		DATA 7 (I)	I/O
		DATA 6 (I)	I/O
		DATA 5 (I)	I/O
		DATA 4 (I)	I/O
		DATA 3 (I)	I/O
		DATA 2 (I)	I/O
		DATA 1 (I)	I/O
DIN (I)	DIN (I)	DATA 0 (I)	I/O
DOUT	DOUT	DOUT	GCK6-I/O
TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS-I/O
TDO	TDO	TDO	TDO-(O)
		CS1	I/O
			ALL OTHERS

Notes:
1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3. $\overline{\text{INIT}}$ is an open-drain output during configuration.



Symbol		Description	Min	Max	Units
T_{IC}	CCLK	$\overline{\text{INIT}}$ (High) setup time	5	-	µs
T_{DC}		D0-D7 setup time	20	-	ns
T_{CD}		D0-D7 hold time	0	-	ns
T_{CCH}		CCLK High time	45	-	ns
T_{CCL}		CCLK Low time	45	-	ns
F_{CC}		CCLK Frequency	-	10	MHz

Notes:
1. If not driven by the preceding DOUT, CS1 *must* remain High until the device is fully configured.

Figure 28: **Express Mode Programming Switching Characteristics**

Setting CCLK Frequency

In Master mode, CCLK can be generated in either of two frequencies. In the default slow mode, the frequency ranges from 0.5 MHz to 1.25 MHz for Spartan/XL devices. In fast CCLK mode, the frequency ranges from 4 MHz to 10 MHz for Spartan/XL devices. The frequency is changed to fast by an option when running the bitstream generation software.

Data Stream Format

The data stream ("bitstream") format is identical for both serial configuration modes, but different for the Spartan-XL family Express mode. In Express mode, the device becomes active when DONE goes High, therefore no length count is required. Additionally, CRC error checking is not supported in Express mode. The data stream format is shown in Table 16. Bit-serial data is read from left to right. Express mode data is shown with D0 at the left and D7 at the right.

The configuration data stream begins with a string of eight ones, a preamble code, followed by a 24-bit length count and a separator field of ones (or 24 fill bits, in Spartan-XL family Express mode). This header is followed by the actual configuration data in frames. The length and number of frames depends on the device type (see Table 17). Each frame begins with a start field and ends with an error check. In serial modes, a postamble code is required to signal the end of data for a single device. In all cases, additional start-up bytes of data are required to provide four clocks for the startup sequence at the end of configuration. Long daisy chains require additional startup bytes to shift the last data through the chain. All start-up bytes are "don't cares".

Table 16: **Spartan/XL Data Stream Formats**

Data Type	Serial Modes (D0...)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0][1]
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b[2]
Data Frame	DATA[n–1:0]	DATA[n–1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFFh
Postamble	01111111b	-
Start-Up Bytes[3]	FFh	FFFFFFFFFFFFFFh

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:
1. Not used by configuration logic.
2. 11111111b for XCS40XL only.
3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC}.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

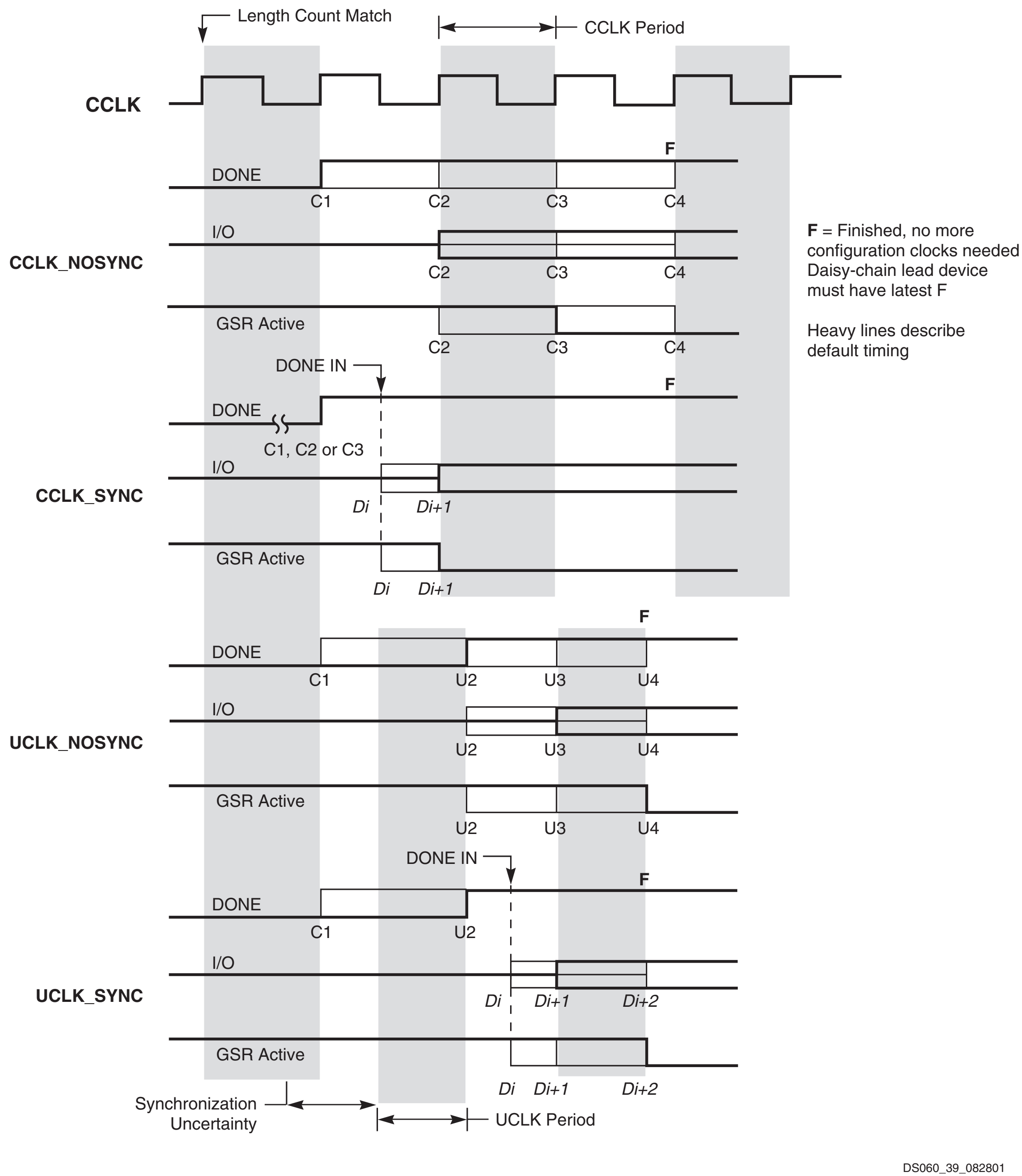


Figure 31: **Start-up Timing**

Configuration Through the Boundary Scan Pins

Spartan/XL devices can be configured through the boundary scan pins. The basic procedure is as follows:

- Power up the FPGA with INIT held Low (or drive the PROGRAM pin Low for more than 300 ns followed by a High while holding INIT Low). Holding INIT Low allows enough time to issue the CONFIG command to the FPGA. The pin can be used as I/O after configuration if a resistor is used to hold INIT Low.
- Issue the CONFIG command to the TMS input.
- Wait for INIT to go High.
- Sequence the boundary scan Test Access Port to the SHIFT-DR state.
- Toggle TCK to clock data into TDI pin.

The user must account for all TCK clock cycles after INIT goes High, as all of these cycles affect the Length Count compare.

For more detailed information, refer to the Xilinx application note, "*Boundary Scan in FPGA Devices*." This application note applies to Spartan and Spartan-XL devices.

Spartan Family Detailed Specifications

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or families. Values are subject to change. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.

Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications.

Spartan Family Absolute Maximum Ratings(1)

Symbol	Description		Value	Units
V_{CC}	Supply voltage relative to GND		–0.5 to +7.0	V
V_{IN}	Input voltage relative to GND(2,3)		–0.5 to V_{CC} +0.5	V
V_{TS}	Voltage applied to 3-state output(2,3)		–0.5 to V_{CC} +0.5	V
T_{STG}	Storage temperature (ambient)		–65 to +150	°C
T_J	Junction temperature	Plastic packages	+125	°C

Notes:
1. Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
2. Maximum DC overshoot (above V_{CC}) or undershoot (below GND) must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
3. Maximum AC (during transitions) conditions are as follows; the device pins may undershoot to –2.0V or overshoot to +7.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
4. For soldering guidelines, see the Package Information on the Xilinx website.

Spartan Family Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V_{CC}	Supply voltage relative to GND, T_J = 0°C to +85°C	Commercial	4.75	5.25	V
	Supply voltage relative to GND, T_J = –40°C to +100°C(1)	Industrial	4.5	5.5	V
V_{IH}	High-level input voltage(2)	TTL inputs	2.0	V_{CC}	V
		CMOS inputs	70%	100%	V_{CC}
V_{IL}	Low-level input voltage(2)	TTL inputs	0	0.8	V
		CMOS inputs	0	20%	V_{CC}
T_{IN}	Input signal transition time		-	250	ns

Notes:
1. At junction temperatures above those listed as Recommended Operating Conditions, all delay parameters increase by 0.35% per °C.
2. Input and output measurement thresholds are: 1.5V for TTL and 2.5V for CMOS.

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines (continued)

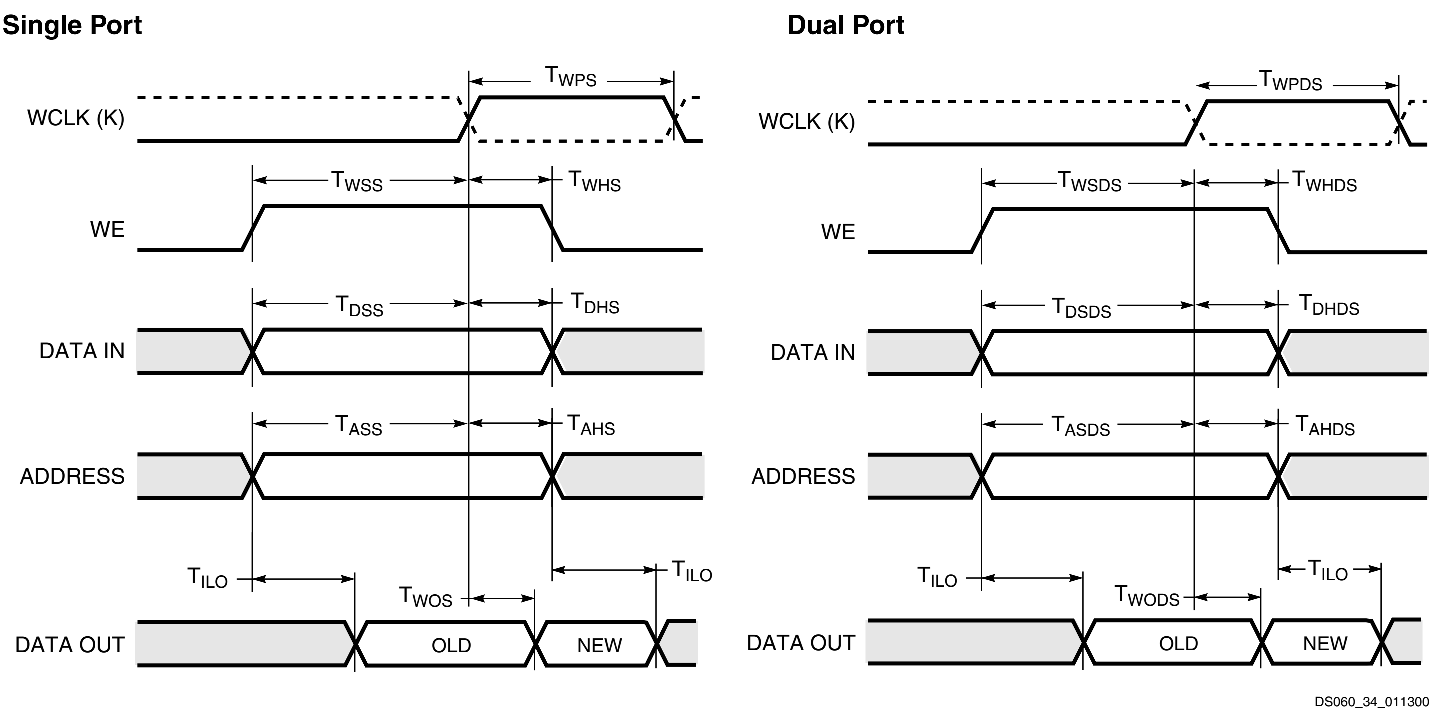
All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and are expressed in nanoseconds unless otherwise noted.

Dual-Port RAM Synchronous (Edge-Triggered) Write Operation Characteristics

Symbol	Dual Port RAM	Size[(1)]	-4		-3		Units
			Min	Max	Min	Max	
Write Operation							
T_{WCDS}	Address write cycle time (clock K period)	16x1	8.0	-	11.6	-	ns
T_{WPDS}	Clock K pulse width (active edge)	16x1	4.0	-	5.8	-	ns
T_{ASDS}	Address setup time before clock K	16x1	1.5	-	2.1	-	ns
T_{AHDS}	Address hold time after clock K	16x1	0	-	0	-	ns
T_{DSDS}	DIN setup time before clock K	16x1	1.5	-	1.6	-	ns
T_{DHDS}	DIN hold time after clock K	16x1	0	-	0	-	ns
T_{WSDS}	WE setup time before clock K	16x1	1.5	-	1.6	-	ns
T_{WHDS}	WE hold time after clock K	16x1	0	-	0	-	ns
T_{WODS}	Data valid after clock K	16x1	-	6.5	-	7.0	ns

Notes:
1. Read Operation timing for 16 x 1 dual-port RAM option is identical to 16 x 2 single-port RAM timing

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Timing



Spartan-XL Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -5 Max	Speed Grade -4 Max	Units
T_{GLS}	From pad through buffer, to any clock K	XCS05XL	1.4	1.5	ns
		XCS10XL	1.7	1.8	ns
		XCS20XL	2.0	2.1	ns
		XCS30XL	2.3	2.5	ns
		XCS40XL	2.6	2.8	ns

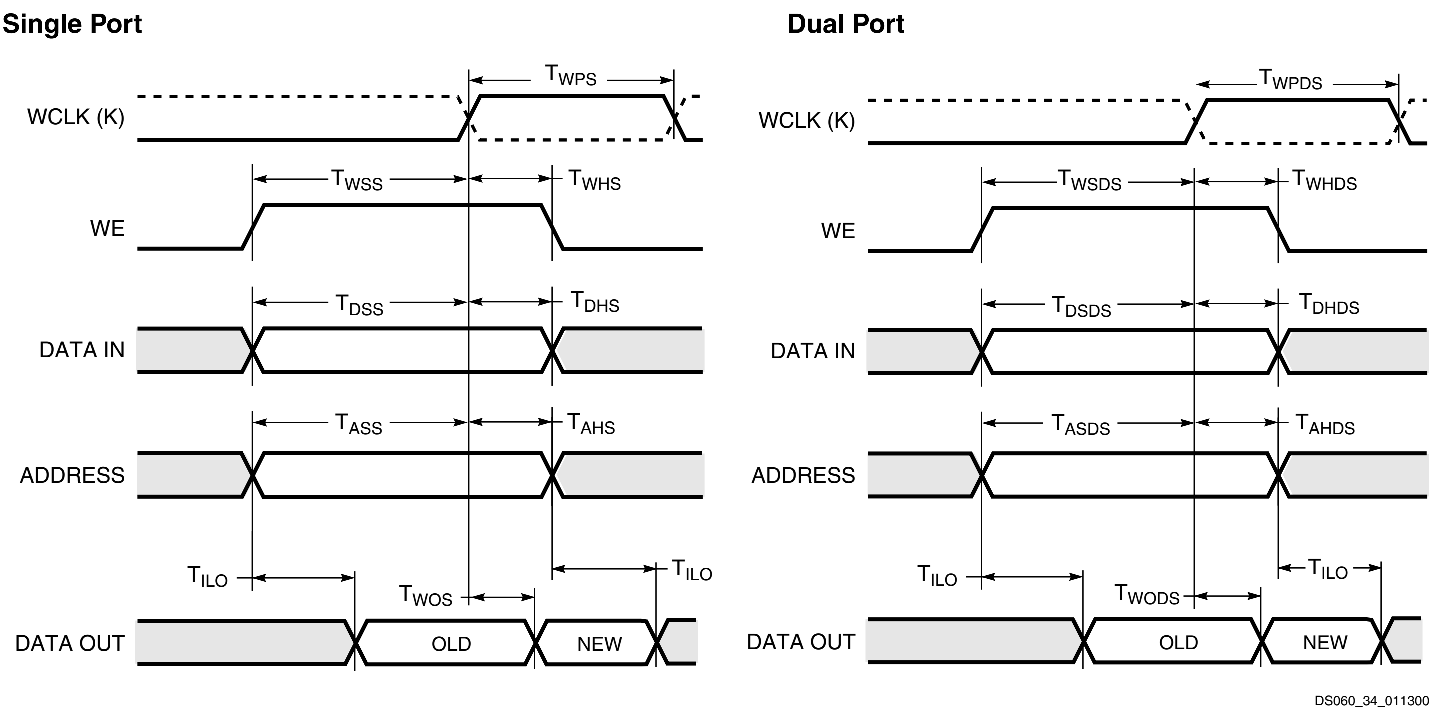
Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines (cont.)

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Dual Port RAM	Size	-5		-4		Units
			Min	Max	Min	Max	
Write Operation[1]							
T_{WCDS}	Address write cycle time (clock K period)	16x1	7.7	-	8.4	-	ns
T_{WPDS}	Clock K pulse width (active edge)	16x1	3.1	-	3.6	-	ns
T_{ASDS}	Address setup time before clock K	16x1	1.3	-	1.5	-	ns
T_{DSDS}	DIN setup time before clock K	16x1	1.7	-	2.0	-	ns
T_{WSDS}	WE setup time before clock K	16x1	1.4	-	1.6	-	ns
	All hold times after clock K	16x1	0	-	0	-	ns
T_{WODS}	Data valid after clock K	16x1	-	5.2	-	6.1	ns

Notes:
1. Read Operation timing for 16 x 1 dual-port RAM option is identical to 16 x 2 single-port RAM timing

Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Timing



Spartan-XL Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -5 Min	-5 Max	-4 Min	-4 Max	Units
Setup Times							
T_{ECIK}	Clock Enable (EC) to Clock (IK)	All devices	0.0	-	0.0	-	ns
T_{PICK}	Pad to Clock (IK), no delay	All devices	1.0	-	1.2	-	ns
T_{POCK}	Pad to Fast Capture Latch Enable (OK), no delay	All devices	0.7	-	0.8	-	ns
Hold Times							
	All Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays							
T_{PID}	Pad to I1, I2	All devices	-	0.9	-	1.1	ns
T_{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.1	-	2.5	ns
T_{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	1.0	-	1.1	ns
T_{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	1.1	-	1.2	ns
Delay Adder for Input with Full Delay Option							
T_{Delay}	$T_{PICKD} = T_{PICK} + T_{Delay}$ $T_{PDLI} = T_{PLI} + T_{Delay}$	XCS05XL	4.0	-	4.7	-	ns
		XCS10XL	4.8	-	5.6	-	ns
		XCS20XL	5.0	-	5.9	-	ns
		XCS30XL	5.5	-	6.5	-	ns
		XCS40XL	6.5	-	7.6	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T_{RRI}	Delay from GSR input to any Q	XCS05XL	-	9.0	-	10.5	ns
		XCS10XL	-	9.5	-	11.0	ns
		XCS20XL	-	10.0	-	11.5	ns
		XCS30XL	-	11.0	-	12.5	ns
		XCS40XL	-	12.0	-	13.5	ns

Notes:
1. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
2. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Table 18: **Pin Descriptions *(Continued)***

Pin Name	I/O During Config.	I/O After Config.	Pin Description
PWRDWN	I	I	PWRDWN is an active Low input that forces the FPGA into the Power Down state and reduces power consumption. When PWRDWN is Low, the FPGA disables all I/O and initializes all flip-flops. All inputs are interpreted as Low independent of their actual level. VCC must be maintained, and the configuration data is maintained. PWRDWN halts configuration if asserted before or during configuration, and re-starts configuration when removed. When PWRDWN returns High, the FPGA becomes operational by first enabling the inputs and flip-flops and then enabling the outputs. PWRDWN has a default internal pull-up resistor.
User I/O Pins That Can Have Special Functions			
TDO	O	O	If boundary scan is used, this pin is the Test Data Output. If boundary scan is not used, this pin is a 3-state output without a register, after configuration is completed. To use this pin, place the library component TDO instead of the usual pad symbol. An output buffer must still be used.
TDI, TCK, TMS	I	I/O or I (JTAG)	If boundary scan is used, these pins are Test Data In, Test Clock, and Test Mode Select inputs respectively. They come directly from the pads, bypassing the IOBs. These pins can also be used as inputs to the CLB logic after configuration is completed. If the BSCAN symbol is not placed in the design, all boundary scan functions are inhibited once configuration is completed, and these pins become user-programmable I/O. In this case, they must be called out by special library elements. To use these pins, place the library components TDI, TCK, and TMS instead of the usual pad symbols. Input or output buffers must still be used.
HDC	O	I/O	High During Configuration (HDC) is driven High until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, HDC is a user-programmable I/O pin.
LDC	O	I/O	Low During Configuration (LDC) is driven Low until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, LDC is a user-programmable I/O pin.
INIT	I/O	I/O	Before and during configuration, INIT is a bidirectional signal. A 1 kΩ to 10 kΩ external pull-up resistor is recommended. As an active Low open-drain output, INIT is held Low during the power stabilization and internal clearing of the configuration memory. As an active Low input, it can be used to hold the FPGA in the internal WAIT state before the start of configuration. Master mode devices stay in a WAIT state an additional 30 to 300 μs after INIT has gone High. During configuration, a Low on this output indicates that a configuration data error has occurred. After the I/O go active, INIT is a user-programmable I/O pin.
PGCK1 - PGCK4 (Spartan)	Weak Pull-up	I or I/O	Four Primary Global inputs each drive a dedicated internal global net with short delay and minimal skew. If not used to drive a global buffer, any of these pins is a user-programmable I/O. The PGCK1-PGCK4 pins drive the four Primary Global Buffers. Any input pad symbol connected directly to the input of a BUFGP symbol is automatically placed on one of these pins.

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100(5)	TQ144	PQ208	PQ240	BG256(5)	CS280(2,5)	Bndry Scan
I/O	-	-	-	P190	B16	A15	23
I/O	-	P117	P166	P191	A16	E14	26
I/O	-	-	P167	P192	C15	C14	29
I/O	-	-	P168	P193	B15	B14	32
I/O	-	-	P169	P194	A15	D14	35
GND	-	P118	P170	P196	GND(4)	GND(4)	-
I/O	-	P119	P171	P197	B14	A14	38
I/O	-	P120	P172	P198	A14	C13	41
I/O	-	-	-	P199	C13	B13	44
I/O	-	-	-	P200	B13	A13	47
VCC	-	-	P173	P201	VCC(4)	D13	-
I/O	P82	P121	P174	P202	C12	B12	50
I/O	P83	P122	P175	P203	B12	D12	53
I/O	-	-	P176	P205	A12	A11	56
I/O	-	-	P177	P206	B11	B11	59
I/O	P84	P123	P178	P207	C11	C11	62
I/O	P85	P124	P179	P208	A11	D11	65
I/O	P86	P125	P180	P209	A10	A10	68
I/O	P87	P126	P181	P210	B10	B10	71
GND	P88	P127	P182	P211	GND(4)	GND(4)	-

2/8/00

Notes:
1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS30XL is not part of the Boundary Scan chain. For the XCS30XL, subtract 1 from all Boundary Scan numbers from GCK3 on (295 and higher).
4. Pads labeled GND(4) or V_{CC}(4) are internally bonded to Ground or V_{CC} planes within the package.
5. CS280 package, and VQ100 and BG256 packages for XCS30 only, discontinued by PDN2004-01

Additional XCS30/XL Package Pins

PQ240

GND Pins					
P22	P37	P83	P98	P143	P158
P204	P219	-	-	-	-
Not Connected Pins					
P195	-	-	-	-	-

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BG256

VCC Pins					
C14	D6	D7	D11	D14	D15
E20	F1	F4	F17	G4	G17
K4	L17	P4	P17	P19	R2
R4	R17	U6	U7	U10	U14
U15	V7	W20	-	-	-

GND Pins					
A1	B7	D4	D8	D13	D17
G20	H4	H17	N3	N4	N17
U4	U8	U13	U17	W14	-
Not Connected Pins					
A7	A13	C8	D12	H20	J3
J4	M4	M19	V9	W9	W13
Y13	-	-	-	-	-

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CS280

VCC Pins					
A1	A7	C10	C17	D13	G1
G1	G19	K2	K17	M4	N16
T7	U3	U10	U17	W13	-
GND Pins					

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280(2,5)	Bndry Scan
O, TDO	P157	P181	A19	B17	0
GND	P158	P182	GND(4)	GND(4)	-
I/O	P159	P183	B18	A18	2
I/O, PGCK4(1), GCK7(2)	P160	P184	B17	A17	5
I/O	P161	P185	C17	D16	8
I/O	P162	P186	D16	C16	11
I/O (CS1(2))	P163	P187	A18	B16	14
I/O	P164	P188	A17	A16	17
I/O	-	-	-	E15	20
I/O	-	-	-	C15	23
I/O	P165	P189	C16	D15	26
I/O	-	P190	B16	A15	29
I/O	P166	P191	A16	E14	32
I/O	P167	P192	C15	C14	35
I/O	P168	P193	B15	B14	38
I/O	P169	P194	A15	D14	41
GND	P170	P196	GND(4)	GND(4)	-
I/O	P171	P197	B14	A14	44
I/O	P172	P198	A14	C13	47
I/O	-	P199	C13	B13	50
I/O	-	P200	B13	A13	53
VCC	P173	P201	VCC(4)	VCC(4)	-
I/O	-	-	A13	A12	56
I/O	-	-	D12	C12	59
I/O	P174	P202	C12	B12	62
I/O	P175	P203	B12	D12	65
I/O	P176	P205	A12	A11	68
I/O	P177	P206	B11	B11	71
I/O	P178	P207	C11	C11	74
I/O	P179	P208	A11	D11	77
I/O	P180	P209	A10	A10	80
I/O	P181	P210	B10	B10	83
GND	P182	P211	GND(4)	GND(4)	-

2/8/00

Notes:
1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS40XL is not part of the Boundary Scan chain. For the XCS40XL, subtract 1 from all Boundary Scan numbers from GCK3 on (343 and higher).
4. Pads labeled GND(4) or V_{CC}(4) are internally bonded to Ground or V_{CC} planes within the package.
5. CS280 package discontinued by PDN2004-01

Additional XCS40/XL Package Pins

PQ240

GND Pins					
P22	P37	P83	P98	P143	P158
P204	P219	-	-	-	-
Not Connected Pins					
P195	-	-	-	-	-

2/12/98

BG256

VCC Pins					
C14	D6	D7	D11	D14	D15
E20	F1	F4	F17	G4	G17
K4	L17	P4	P17	P19	R2
R4	R17	U6	U7	U10	U14
U15	V7	W20	-	-	-
GND Pins					
A1	B7	D4	D8	D13	D17
G20	H4	H17	N3	N4	N17
U4	U8	U13	U17	W14	-

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CS280

VCC Pins					
A1	A7	B5	B15	C10	C17
D13	E3	E18	G1	G19	K2
K17	M4	N16	R3	R18	T7
U3	U10	U17	V5	V15	W13
GND Pins					
E5	E7	E8	E9	E11	E12
E13	G5	G15	H5	H15	J5
J15	L5	L15	M5	M15	N5
N15	R7	R8	R9	R11	R12
R13	-	-	-	-	-

5/19/99

Revision History

The following table shows the revision history for this document.

Date	Version	Description
11/20/98	1.3	Added Spartan-XL specs and Power Down.
01/06/99	1.4	All Spartan-XL -4 specs designated Preliminary with no changes.
03/02/00	1.5	Added CS package, updated Spartan-XL specs to Final.
09/19/01	1.6	Reformatted, updated power specs, clarified configuration information. Removed T_{SOL} soldering information from Absolute Maximum Ratings table. Changed Figure 26: Slave Serial Mode Characteristics: T_{CCH}, T_{CCL} from 45 to 40 ns. Changed Master Mode Configuration Switching Characteristics: T_{CCLK} min. from 80 to 100 ns. Added Total Dist. RAM Bits to Table 1; added **Start-Up**, page 36 characteristics.
06/27/02	1.7	Clarified Express Mode pseudo daisy chain. Added new Industrial options. Clarified XCS30XL CS280 V_{CC} pinout.
06/26/08	1.8	Noted that PC84, CS144, and CS280 packages, and VQ100 and BG256 packages for XCS30 only, are discontinued by **PDN2004-01**. Extended description of recommended maximum delay of reconfiguration in **Delaying Configuration After Power-Up**, page 35. Added reference to Pb-free package options and provided link to **Package Specifications**, page 81. Updated links.
03/01/13	2.0	The products listed in this data sheet are obsolete. See **XCN10016** and **XCN11010** for further information.